

Inductively Coupled Plasma Spectroscopy

Inductively Coupled Plasma Spectroscopy techniques are "wet" sampling methods where samples are introduced in liquid form for analysis.

In plasma emission spectroscopy (OES), a sample solution is introduced into the core of inductively coupled argon plasma (ICP), which generates temperature of approximately 8000°C. At this temperature all elements become thermally excited and emit light at their characteristic wavelengths. This light is collected by the spectrometer and passes through a diffraction grating that serves to resolve the light into a spectrum of its constituent wavelengths. Within the spectrometer, this diffracted light is then collected by wavelength and amplified to yield an intensity measurement that can be converted to an elemental concentration by comparison with calibration standards.

In plasma mass spectroscopy (MS), the inductively coupled argon plasma (ICP) is once again used as an excitation source for the elements of interest. However in contrast to OES, the plasma in ICP-MS is used to generate ions that are then introduced to the mass analyzer. These ions are then separated and collected according to their mass to charge ratios. The constituents of an unknown sample can then be identified and measured. ICP-MS offers extremely high sensitivity to a wide range of elements.

Strengths	Limitations
Up to 70 elements can be determined simultaneously in a single sample analysis.	The emission spectra are complex and inter-element interferences are possible if the wavelength of the element of interest is very close to that of another element.
The useful working range is over several orders of magnitude.	During Mass Spectrometry, the common matrix elements and other molecular species can interfere with the measurement of some elements. Doubly charged or molecular ionic species can create difficulties in quantifications.
Instrumentation is suitable to automation, thus enhancing accuracy, precision and throughput.	The sample to be analyzed must be digested prior to analysis in order to dissolve the element(s) of interest.

EAG Locations

United States

Arizona
903 S. Rural Road, #101-388
Tempe, AZ 85281
480 239-0602
602 470-2655 Fax
info.az@eaglabs.com

Massachusetts
10 Centennial Drive
Peabody, MA 01960
978 278-9500
978 278-9501 Fax
info.ma@eaglabs.com

New York
SHIVA Technologies
6707 Brooklawn Parkway
Syracuse, NY 13211
315 431 9900
315 431 9800 Fax
info.ny@eaglabs.com

California
810 Kifer Road
Sunnyvale, CA 94086
408 530-3500
408 530-3501 Fax
info.ca@eaglabs.com

Minnesota
18725 Lake Drive East
Chanhassen, MN 55317
952 828-6411
952 828-6449 Fax
info.mn@eaglabs.com

North Carolina
616 Hutton St., Ste. 101
Raleigh, NC 27606
919 829-7041
919 829-5518 Fax
info.nc@eaglabs.com

1135 E. Arques Avenue
Sunnyvale, CA 94085
408 738-3033
408 738-3035 Fax

New Jersey
104 Windsor Center Dr., Ste. 101
East Windsor, NJ 08520
609 371-4800
609 371-5666 Fax
info.nj@eaglabs.com

Texas
425 Round Rock West Dr., Ste. 100
Round Rock, TX 78681
512 671-9500
512 671-9501 Fax
info.tx@eaglabs.com

785 Lucerne Drive
Sunnyvale, CA 94085
408 737-3892
408 737-3916 Fax

International Locations

Evans Analytical Group - Shanghai
Ste. 102, Building 44, 1387 Zhangdong Road
Pudong Area, Shanghai, China 201204
86 21 6879 6088
86 21 6879 9086 Fax
info.cn@eaglabs.com

Nano Science Corporation
7F, Sumitomo Bldg., Higashi Ikebukuro 1-10-1
Toshima-Ku, Tokyo 170-0013, Japan
81 3 5396 0531
81 3 5396 1930 Fax
info.jp@eaglabs.com

Shiva Technologies Europe SAS
94, chemin de la Peyrette
31170 Tournefeuille, France
33 5 61 73 15 29
33 5 61 73 15 67 Fax
info.fr@eaglabs.com

Evans Taiwan LLC
5F-1, No. 31 PuDing Road
HsinChu, Taiwan, 300 R.O.C.
886 3 5632303
886 3 5632306 Fax
info.tw@eaglabs.com

Cascade Scientific GmbH
Industriepark Höchst, Building G 865
D-65926 Frankfurt am Main, Germany
49 (0) 693053213
49 (0) 69307941 Fax
info.de@eaglabs.com

Cascade Scientific Ltd.
ETC Building
Brunel Science Park
Uxbridge UB8 3PH, U.K.
44 (0) 1895 811194
44 (0) 1895 810350 Fax
info.uk@eaglabs.com

WWW.EAGLABS.COM

